

Supplementary Information for

Substrate and drying effect in shape and ordering of micelles inside CTAB-silica mesostructured films

P. Chatterjee†, S. Hazra†* and H. Amenitsch‡

†Surface Physics Division, Saha Institute of Nuclear Physics, 1/AF Bidhannagar, Kolkata 700064, India

‡Institute of Biophysics and Nanosystem Research, Austrian Academy of Sciences,
Schmiedlstrasse 6, 8042 Graz, Austria

*Corresponding Author: satyajit.hazra@saha.ac.in

Estimation of the size of the CTAB micelles: To estimate the size of micelles, x-ray reflectivity (XR) measurement was carried out for the film containing CTAB micelles only. Measured XR profile is shown in Figure S1. First, second and third order of (11) or (02) Bragg peaks (corresponding to the 2D-hexagonal structure) are observed. The value of $d_{11} = d_{02}$ has been estimated from the slope of the peak-position vs. order of Bragg peak plot, as shown in the inset of the Figure S1. Using the relation, $2R = 2d_{11}/\sqrt{3}$, the size of the CTAB micelles has been estimated, which is ~ 3 nm.

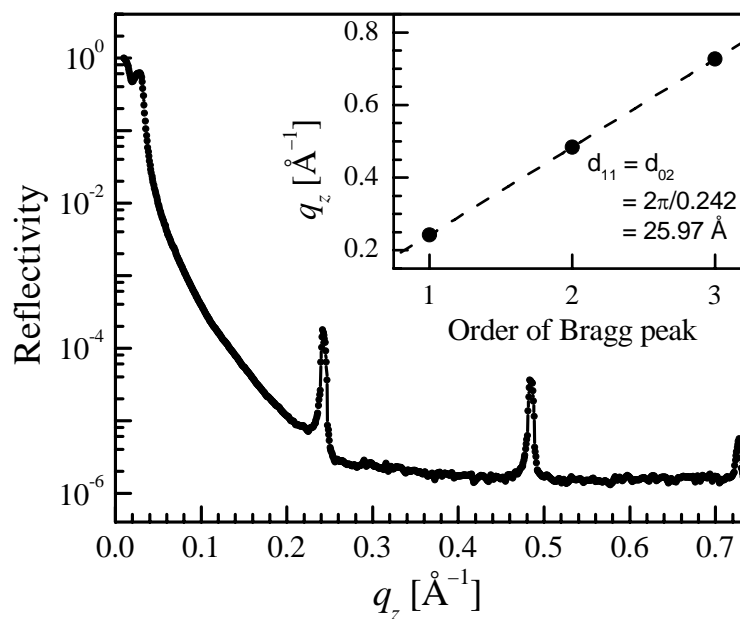


Figure S1: XR profile of CTAB micelles film on Si. Inset: corresponding (11) or (02) Bragg peak positions for different order. Value of d_{11} obtained from the slope is indicated.